

Fujitsu LIFEBOOK® E744 Notebook PC

Environmental MIL-STD-810G

Testing Summary

P/N: FPC65-7087-01
REV: A

Equipment tested	Fujitsu LIFEBOOK E744	
Independent test company	Quanta Laboratories, 3199 De La Cruz Boulevard, Santa Clara, CA95054 http://www.quantalabs.com/	American Association for Laboratory Accreditation: certificate #2454.01/#2454.02 Valid to August 31, 2014
Independent test company	ENVIRON LABORATORIES LLC, 9725 Girard Ave, South Minneapolis, MN 55431-2621 http://www.environlab.com/index.html	American Association for Laboratory Accreditation: certificate #1719.01 Valid to August 31, 2015



Fujitsu LIFEBOOK E744

Notes: All environmental testing listed in the table below was performed and reported independently by accredited testing companies listed above.

Documented MIL-STD-810G testing guidelines were followed, a summary listing of the tests are presented in the following table.

LIFEBOOK E744 Notebook PC MIL-STD-810G Testing Summary Table

#	Test Listing	Test Method	Description/Parameters	Result ^{1,2}
1	Altitude	MIL-STD-810G Method 500.5 Procedures I & II	Storage/Air Transport test at 30,000 ft, duration 1 hour, unit is non-operational Operational/Air Carriage test at 15,000 ft, duration 1 hour, unit is operational	Pass
2	Low temperature	MIL-STD-810G Method 502.5 Procedures I & II	Non-operational test at -30°C, duration 7 hours, unit is non-operational Operational test at -20°C, duration 5 hours, unit is operational	Pass
3	High temperature	MIL-STD-810G Method 501.5 Procedures I & II	Non-operational test at +70°C duration 4 hours, unit is non-operational Operational test at +60°C duration 4 hours, unit is operational	Pass
4	Humidity	MIL-STD-810G Method 507.5 Procedure II	Aggravated humidity Temperature cycled between 30°C and 60°C Test duration: ten 24-hours cycles. Relative humidity maintained at 95% Unit is non-operational, functional test after 5th and 10th cycles	Pass
5	Functional shock	MIL-STD-810G Method 516.6 Procedure I	Non-operational test - 40G, 11 ms, saw-tooth pulse configuration, 3 shocks, ± per axis, unit is non-operational Operational test - 20G, 11 ms, half-sine pulse configuration, 3 shocks, ± per axis, unit is operational	Pass
6	Vibration, integrity	MIL-STD-810G Method 514.6 Category 24	Non-operational test, Minimum integrity test 20-2000Hz; 20-1000 Hz at 0.04G ² /Hz, 1000 2000Hz at 6dB, overall 7.7G RMS; test profile see in figure 514.6E-1. Test duration: 1 hours x 3 axis. Unit is non-operational	Pass
7	Vehicle Vibration	MIL-STD-810G Method 514.6 Category 20	Operational test - Ground vehicle, US Highways 1,000 miles of transportation, test profile see figure 514.6C-I and table 514.6C-II. Test duration: 1 hours x 3 axis. Unit is operational.	Pass
8	Blowing Dust	MIL-STD-810G Method 510.5 Procedure I	Non-operational test duration 6 hours, dust density 10±7 g/m ³ , air velocity 8.9m/s, 140 mesh silica flower at 24°C ambient. Unit is non-operational Operational test duration 6 hours, dust density 10±7 g/m ³ , air velocity 8.9m/s, 140 mesh silica flower at 35°C ambient. Unit is operational	Pass
9	Transit Drop	MIL-STD-810G Method 516.6	Non-operational test, transit drop from 30" height on 2" plywood. One drop on 4 corners, 8 edges, 6 face on a single test unit. Unit is closed and non-operational.	Refer footnote*

¹Pass for Operational test indicates that unit remained operational during the entirety of the test. After the test ran and verified one complete pass of Fujitsu proprietary diagnostic software.

²Pass for Non-operational test indicates that after the test unit powered, booted to Windows OS, ran and verified one complete pass of Fujitsu proprietary diagnostic software.

*Test unit passed functional performance test after each drop and remained operational after all tests were completed. Some mechanical damage was observed.

Contact
 FUJITSU AMERICA, INC.
 Address: 1250 East Arques Avenue Sunnyvale, CA 94085-3470, U.S.A.
 Telephone: 800 831 3183 or 408 746 6000
 Website: <http://solutions.us.fujitsu.com>
 Contact Form: <http://solutions.us.fujitsu.com/contact>

Disclaimer
 ©2014 Fujitsu America, Inc. All rights reserved.
 Fujitsu, the Fujitsu logo and LIFEBOOK are trademarks or registered trademarks of Fujitsu Limited in the United States and other countries. All other trademarks referenced herein are the property of their respective owners.
 The information in this document is subject to change without notice.
 Fujitsu America, Inc. ("FAT") makes no warranty of any kind with regard to this material, including, but not limited to, the implied warranties of merchantability and fitness for a particular purpose.
 Test results are not a guarantee of future performance under identified test conditions, nor does it imply that it will meet the contract requirements of Department of Defense.